


<b>Search Notes</b>  	<b>Application/Control No.</b>  10573155	<b>Applicant(s)/Patent Under Reexamination</b>  MAEKAWA ET AL.
	<b>Examiner</b>  Thien F Tran	<b>Art Unit</b>  2895

SEARCHED			
Class	Subclass	Date	Examiner
438	406, 455, 458	02/24/2009	TT

SEARCH NOTES		
Search Notes	Date	Examiner
Search history printout	02/24/2009	TT
Search history printout	02/25/2009	TT
Search history printout	08/11/2009	TT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
All		08/11/2009	TT

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